

AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:Claim 1. (Currently Amended).

A process for producing a silicon single crystal, comprising pulling a silicon single crystal from a silicon melt which is contained in a crucible having a crucible wall and having a crucible diameter of at least 450 mm,

placing a heat shield above said crucible; and said silicon single crystal being pulled with a diameter of at least 200 mm; and

exposing the silicon melt to ~~an influence of a magnetic field consisting of~~ a traveling magnetic field which exerts a substantially vertically oriented force on the melt in a region of the crucible wall and

applying the magnetic field with an intensity which is sufficient to attenuate low-frequency temperature fluctuations in the melt.

~~except for said traveling magnetic field no further magnetic field being applied to the melt.~~

Claim 2. (Original).

The process as claimed in claim 1,
wherein the silicon single crystal is pulled with an oxygen
concentration of at least $5 * 10^{17}$ atoms per cm^3 .

Claims 3-13: (Canceled).Claim 14. (Currently Amended).

A process for producing a silicon single crystal, comprising
pulling a silicon single crystal from a silicon melt which
is contained in a crucible having a crucible wall and having a
crucible diameter of at least 450 mm,

placing a heat shield above said crucible; and said silicon
single crystal being pulled with a diameter of at least 200 mm;
and

exposing the silicon melt to ~~an influence of~~ a magnetic
field consisting of a traveling magnetic field which exerts a
substantially vertically oriented force on the melt in a region
of the crucible wall; and

applying the magnetic field with an intensity which is
sufficient to attenuate low-frequency temperature fluctuations in
the melt; and

vertically upwardly oriented force on the melt in a region of the crucible wall, and

applying the magnetic field with an intensity which is sufficient to attenuate low-frequency temperature fluctuations in the melt.

Claim 18. (New): A process for producing a silicon single crystal, comprising pulling a silicon single crystal from a silicon melt which is contained in a crucible having a crucible wall and having a crucible diameter of at least 450 mm,

placing a heat shield above said crucible; and said silicon single crystal being pulled with a diameter of at least 200 mm; and

exposing the silicon melt to a magnetic field consisting of a traveling magnetic field which exerts a substantially vertically downwardly oriented force on the melt in a region of the crucible wall, and

applying the magnetic field with an intensity which is sufficient to attenuate low-frequency temperature fluctuations in the melt.